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<b>INFORMATION DISCLOSURE CITATION FORM FOR PATENT APPLICATION (FORM PTO-1449) (Substitute)</b>		Docket No.: 904.0101.U2(US)	Serial No. <i>10/824,959</i>		
		Applicant(s): Xiao et al.			
		Filing Date: <u>herewith</u> <i>4/14/2004</i>	Group: 2818		
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Examiner Initials	Document Number (Number-Kind Code)	Publication Date (MM-DD-YYYY)	Name of Patentee or Applicant	Class	Sub-class
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Examiner's Signature: <u>ANH D. MAI</u>			Date Considered: <i>7/19/05</i>		
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